

Lecturer Umer Javed

Department of Electronic Engineering,
Faculty of Engineering & Technology,
International Islamic University, Islamabad.

Phone: 051-9019561

Fax: 051-9258025

Email: umer.javed@iiu.edu.pk



Experience

1. Lecturer, Faculty of Engineering & Technology, IIUI.
2. Lecturer, Faculty of IT & Engineering, NUML, Islamabad.
3. Intern BSS Deployment Engineer, W.L.L , V-PTCL.

Education

1. PhD in Electrical Engineering *(In Progress), School of Engineering & Applied Sciences, Isra University, Islamabad Campus
2. MS. Electronic Engineering, Specialization in Signal & Image Processing, IIUI.

Honors & Awards

1. Secured 3rd position in MSEE '07 Batch at IIUI.
2. Technical Reviewer for IET Journal of Image Processing.

Books & Others

1. **Title:** Multichannel Image Deconvolution; Application to Sparse Images.
ISBN/13 No: 978-3-639-33042-7, **VDM Publishers, Germany, March 2011.**

Publications

- **U. Javed**, M. M. Riaz, A. Ghafoor and T. A. Cheema, "Local Features and Takagi Sugeno Fuzzy Logic based Medical Image Segmentation", (Conditionally accepted) Radio Engineering Journal, June 2013.
- **U. Javed**, M. M. Riaz, A. Ghafoor, and T. A. Cheema, "MRI brain classification using texture features, fuzzy weighting and support vector machine," Progress In Electromagnetics Research B, Vol. 53, 73-88, 2013.

- **U. Javed**, M. M. Riaz, A. Ghafoor and T. A. Cheema, “Fuzzy Logic and Local Features based Medical Image Segmentation”, (Accepted) Int’l Conference on Image Processing, September 2013.
- **U. Javed**, M. M. Riaz, T. A. Cheema and H. M. F. Zafar, “Detection of Lung Tumor in CE CT Images by using Weighted Support Vector Machines”, Int’l Bhurban Conference on Applied Sciences & Technology, January 2013.
- **U. Javed**, M. M. Riaz and T. A. Cheema, “Multichannel Blind Image Deconvolution”, Int’l Bhurban Conference on Applied Sciences & Technology, January 2012.
- **U. Javed**, M. M. Riaz and T. A. Cheema, “An Iterative technique for Multichannel Blind Image Deconvolution”, Int’l Conference on Advance Modeling and Simulation, Vol. 1, No. 1, pp. 130-135. November 2011.